Abstracts

A Simple Technique for the Accurate Determination of the Microwave Dielectric Constant for Microwave Integrated Circuit Substrates (Correspondence)

L.S. Napoli and J.J. Hughes. "A Simple Technique for the Accurate Determination of the Microwave Dielectric Constant for Microwave Integrated Circuit Substrates (Correspondence)." 1971 Transactions on Microwave Theory and Techniques 19.7 (Jul. 1971 [T-MTT] (Special Issue on Microwave Integrated Circuits)): 664-665.

A method of determining the microwave dielectric constant of microwave integrated circuit substrates is described. The technique is especially suitable to substrates being prepared for MICs since they are, in general, regular, rectangular, and, therefore, simple resonators. The dielectric constant using this technique has been determined in the 2- to 12-GHz range for GaAs (epsilon R = 12.46), sapphire (epsilon R = 9.37), polyguide (epsilon = 2.33), and Alsimag 772 (epsilon R = 10.08).

❑ Return to main document.